

LOW VOLTAGE QUAD 2 CHANNEL MULTIPLEXER

- **HIGH SPEED:**
 $t_{PD} = 5 \text{ ns (TYP.) at } V_{CC} = 3.3\text{V}$
- **INPUT & OUTPUT TTL COMPATIBLE LEVELS**
- **LOW POWER DISSIPATION:**
 $I_{CC} = 4 \mu\text{A (MAX.) at } T_A = 25^\circ\text{C}$
- **LOW NOISE:**
 $V_{OLP} = 0.2\text{V (TYP.) at } V_{CC} = 3.3\text{V}$
- **75Ω TRANSMISSION LINE OUTPUT DRIVE CAPABILITY**
- **SYMMETRICAL OUTPUT IMPEDANCE:**
 $|I_{OH}| = |I_{OL}| = 12 \text{ mA (MIN)}$
- **PCI BUS LEVELS GUARANTEED AT 24mA**
- **BALANCED PROPAGATION DELAYS:**
 $t_{PLH} \cong t_{PHL}$
- **OPERATING VOLTAGE RANGE:**
 $V_{CC} \text{ (OPR)} = 2\text{V to } 3.6\text{V (1.2V Data Retention)}$
- **PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 157**
- **IMPROVED LATCH-UP IMMUNITY**

DESCRIPTION

The LVQ157 is a low voltage CMOS QUAD 2-CHANNEL MULTIPLEXER fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology. It is ideal for low power and low noise 3.3V applications.



M
(Micro Package)



T
(TSSOP Package)

ORDER CODES :

74LVQ157M

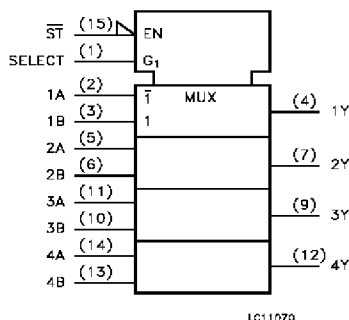
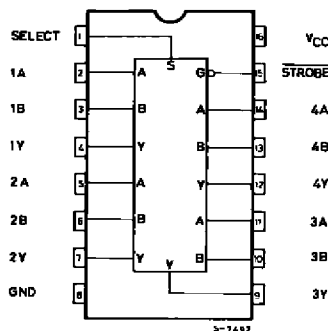
74LVQ157T

It has better speed performance at 3.3V than 5V LSTTL family combined with the true CMOS low power consumption.

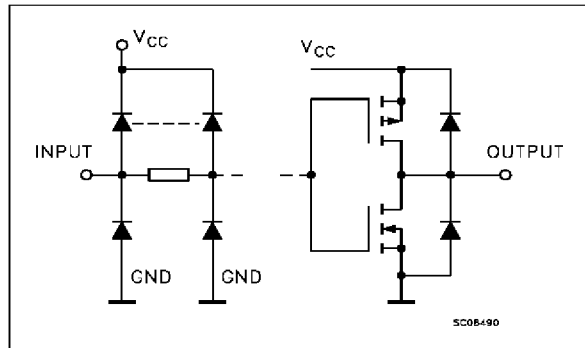
It consists of four 2-input digital multiplexers with common select and strobe inputs. When strobe input is held high selection of data is inhibit and all the outputs become low. The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
1	SELECTED	Common Data Select Input
2, 5, 11, 14	1A to 4A	Data Inputs From Source A
3, 6, 10, 13	1B to 4B	Data Inputs From Source B
4, 7, 9, 12	1Y to 4Y	Multiplexer Outputs
15	$\overline{\text{STROBE}}$	Strobe Input
8	GND	Ground (0V)
16	V _{CC}	Positive Supply Voltage

TRUTH TABLE

INPUT				OUTPUT
$\overline{\text{STROBE}}$	SELECT	A	B	Y
H	X	X	X	L
L	L	L	X	L
L	L	H	X	H
L	H	X	L	L
L	H	X	H	H

X: "H" or "L"

ABSOLUTE MAXIMUM RATING

Symbol	Parameter	Value	Unit
V _{CC}	Supply Voltage	-0.5 to +7	V
V _I	DC Input Voltage	-0.5 to V _{CC} + 0.5	V
V _O	DC Output Voltage	-0.5 to V _{CC} + 0.5	V
I _{IK}	DC Input Diode Current	± 20	mA
I _{OK}	DC Output Diode Current	± 20	mA
I _O	DC Output Current	± 50	mA
I _{CC} or I _{GND}	DC V _{CC} or Ground Current	± 200	mA
T _{stg}	Storage Temperature	-65 to +150	°C
T _L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V _{CC}	Supply Voltage (note 1)	2 to 3.6	V
V _I	Input Voltage	0 to V _{CC}	V
V _O	Output Voltage	0 to V _{CC}	V
T _{op}	Operating Temperature:	-40 to +85	°C
dt/dv	Input Rise and Fall Time (V _{CC} = 3V) (note 2)	0 to 10	ns/V

1) Truth Table guaranteed: 1.2V to 3.6V

2) V_{IN} from 0.8V to 2V

DC SPECIFICATIONS

Symbol	Parameter	Test Conditions			Value					Unit
		V _{CC} (V)			T _A = 25 °C			-40 to 85 °C		
					Min.	Typ.	Max.	Min.	Max.	
V _{IH}	High Level Input Voltage	3.0 to 3.6			2.0			2.0		V
V _{IL}	Low Level Input Voltage						0.8		0.8	V
V _{OH}	High Level Output Voltage	3.0	V _I ^(*) = V _{IH} or V _{IL}	I _O =-50 μA	2.9	2.99		2.9		V
				I _O =-12 mA	2.58			2.48		
				I _O =-24 mA				2.2		
V _{OL}	Low Level Output Voltage	3.0	V _I ^(*) = V _{IH} or V _{IL}	I _O =50 μA		0.002	0.1		0.1	V
				I _O =12 mA		0	0.36		0.44	
				I _O =24 mA					0.55	
I _I	Input Leakage Current	3.6	V _I = V _{CC} or GND				±0.1		±1	μA
I _{CC}	Quiescent Supply Current	3.6	V _I = V _{CC} or GND				4		40	μA
I _{OLD}	Dynamic Output Current (note 1, 2)	3.6	V _{OLD} = 0.8 V max					36		mA
I _{OHD}			V _{OHD} = 2 V min					-25		mA

1) Maximum test duration 2ms, one output loaded at time

2) Incident wave switching is guaranteed on transmission lines with impedances as low as 50 Ω.

(*) All outputs loaded.

DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Conditions		Value					Unit
		V _{CC} (V)		T _A = 25 °C			-40 to 85 °C		
				Min.	Typ.	Max.	Min.	Max.	
V _{OLP}	Dynamic Low Voltage	3.3	C _L = 50 pF		0.2	0.8			V
V _{OLV}	Quiet Output (note 1, 2)			-0.8	0.2				
V _{IHD}	Dynamic High Voltage Input (note 1, 3)	3.3				2			
V _{ILD}	Dynamic Low Voltage Input (note 1, 3)	3.3		0.8					

1) Worst case package

2) Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V, (n - 1) outputs switching and one output at GND

3) max number of data inputs (n) switching. (n-1) switching 0V to 3.3V. Inputs under test switching: 3.3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}). f=1MHz

AC ELECTRICAL CHARACTERISTICS ($C_L = 50 \text{ pF}$, $R_L = 500 \Omega$, Input $t_r = t_f = 3 \text{ ns}$)

Symbol	Parameter	Test Condition		Value					Unit
		V _{CC} (V)		T _A = 25 °C			-40 to 85 °C		
				Min.	Typ.	Max.	Min.	Max.	
t _{PLH} t _{PHL}	Propagation Delay Time (SELECT-Y)	2.7			7.5	15		17	ns
		3.3 ^(*)			6.5	11		12	
t _{PLH} t _{PHL}	Propagation Delay Time (STROBE-Y)	2.7			7	15		17	ns
		3.3 ^(*)			6	11		12	
t _{PLH} t _{PHL}	Propagation Delay Time (A,B-Y)	2.7			6	11		13	ns
		3.3 ^(*)			5	8		9	
t _{OSLZ} t _{OSH}	Output to Output Skew Time (note 1, 2)	2.7			0.5	1.5		1.5	ns
		3.3 ^(*)			0.5	1.5		1.5	

1) Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW

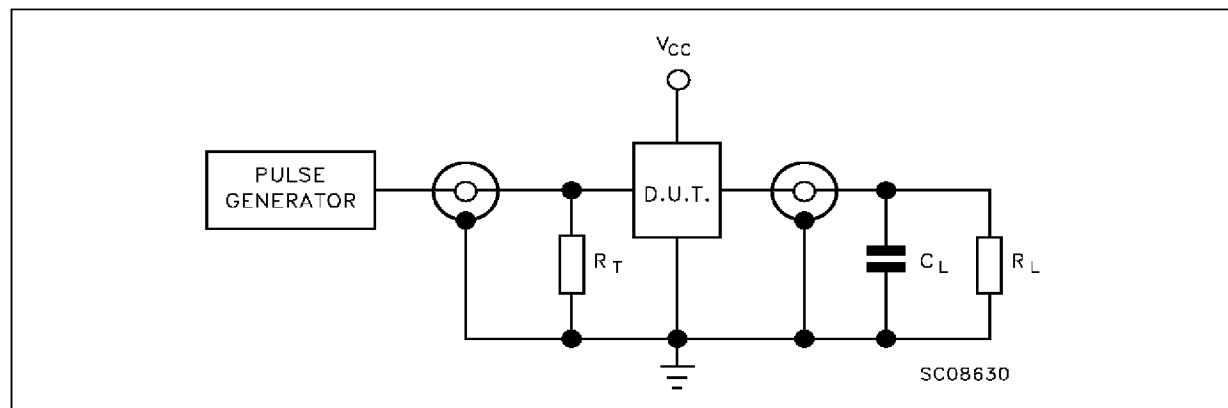
2) Parameter guaranteed by design

(*) Voltage range is $3.3\text{V} \pm 0.3\text{V}$

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions		Value					Unit
		V _{CC} (V)		T _A = 25 °C			-40 to 85 °C		
				Min.	Typ.	Max.	Min.	Max.	
C _{IN}	Input Capacitance	3.3			5				pF
C _{PD}	Power Dissipation Capacitance (note 1)	3.3	f _{IN} = 10 MHz		24				pF

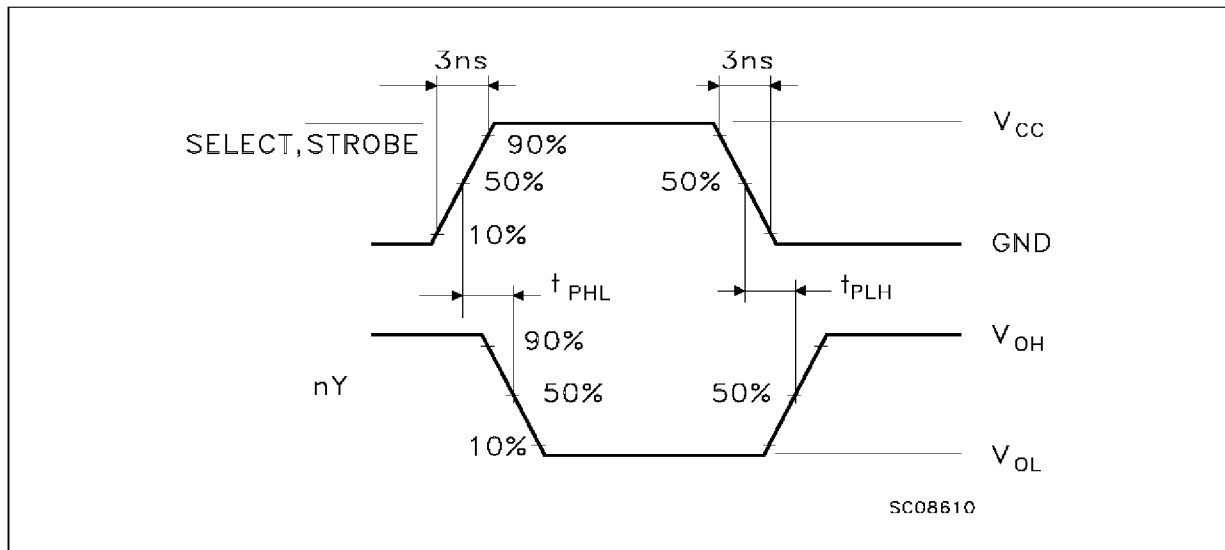
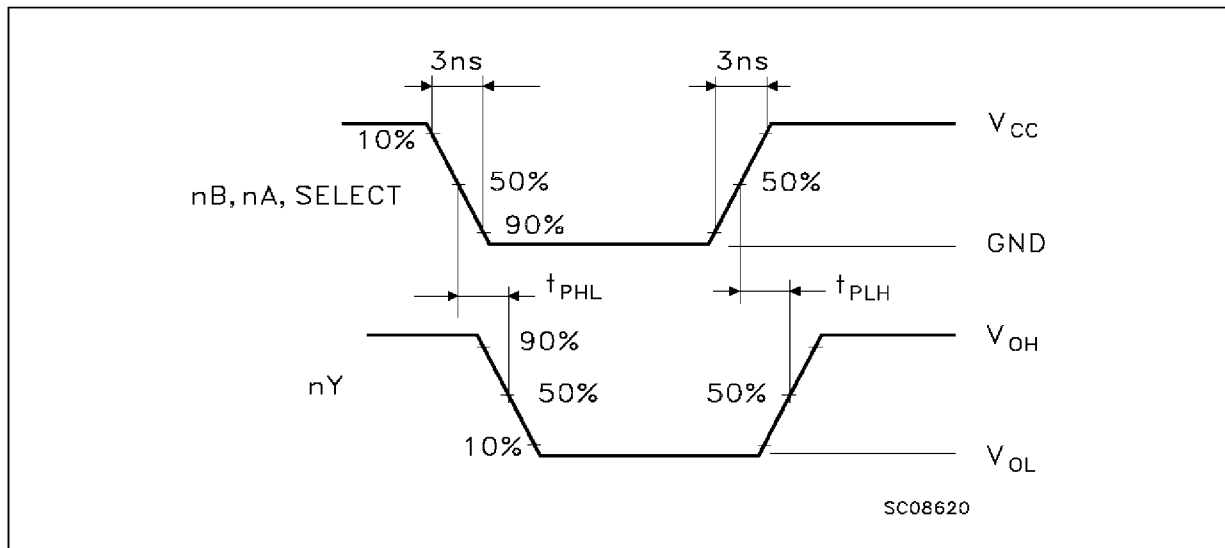
1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. $I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/n$ (per circuit)

TEST CIRCUIT

$C_L = 50 \text{ pF}$ or equivalent (includes jig and probe capacitance)

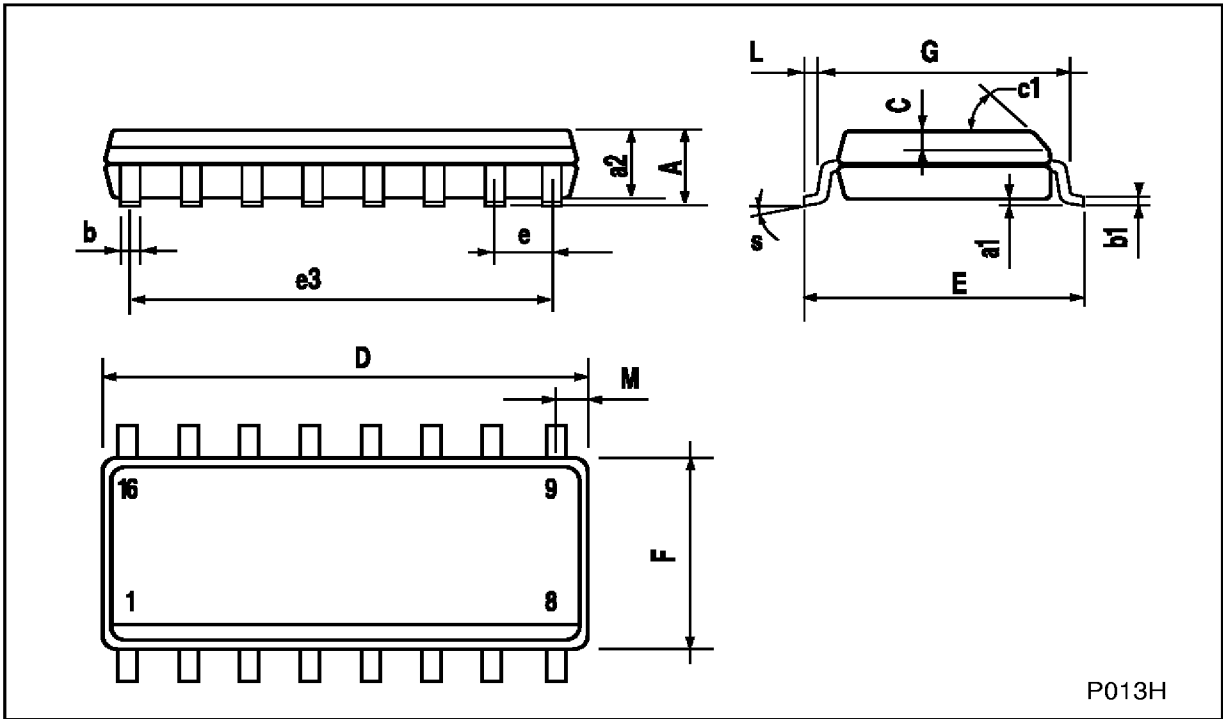
$R_L = R_T = 500 \Omega$ or equivalent

$R_T = Z_{OUT}$ of pulse generator (typically 50Ω)

WAVEFORM 1: PROPAGATION DELAYS FOR INVERTING CONDITIONS**WAVEFORM 2: PROPAGATION DELAYS FOR NON-INVERTING CONDITIONS**

SO16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.004		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1	45 (typ.)					
D	9.8		10	0.385		0.393
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		8.89			0.350	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.62			0.024
S	8 (max.)					



P013H

TSSOP16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2		0.9			0.354	
b	0.18		0.30	0.0071		0.0118
c	0.09		0.18	0.0035		0.0071
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°	4°	8°	0°	4°	8°
L	0.50	0.60	0.70	0.020	0.024	0.028

